The MiniCactus sensor development line : towards HV-CMOS Monolithic sensors with 20 ps resolution

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Small noise \rightarrow choice of technology, small detector capacitance High dv/dt \rightarrow High electric field (but Vd saturates around 1 V/µm) Intrinsic amplification

Amplitude variation \rightarrow Timewalk, corrected offline

Non-homogeneous energy deposition \rightarrow cannot be corrected, minimized by design

Saturated drift velocity in sensor volume \rightarrow Uniform weighting field

Parallel plate geometry, easier for big pixels \rightarrow Large electrode designs



MiniCACTUS V1 Sensor Chip

≈2 5 mm 8 3 6 en les en l'arten enten enten Layout of MiniCACTUS

Block diagram of the MiniCACTUS chip (not to scale)

Pixel Flavors :

Pixels 3 & 7 : 1 mm x 1 mm baseline pixels
Pixels 2, 4, 6 & 8 : 0.5 mm x 1 mm pixels
Pixel 8 : 0.5 mm x 1 mm pixel with in-pixel AC coupling capacitor (20pF)
Pixels 1 : 50 μm x 50 μm test pixel
Pixels 5 : 50 μm x 150 μm test pixel

- MiniCACTUS is a small detector prototype designed in order to address the *low S/N issue* observed on previous CACTUS large size demonstrator
- FE integrated at column level, pixels mostly passive
- On-chip Slow Control, DACs, bias circuitry
- 2 discriminated digital (LVDS) and 2 analog monitoring (*slower than CSA output*) outputs for 2 columns
- 2 small pixels implemented as test structures to study charge collection (*FEs* not power optimized)
- Some detectors thinned to 100, 200,
 300µm and than post-processed for backside polarization after fabrication

TYPICAL WAVEFORMS OBSERVED DURING TESTBEAM



 \rightarrow Ringing on **Digital Output** due to coupling from the digital buffers (known problem from in-lab tests, negative impact on TW corrections from digital ToT)

180 GeV/c muon data taken at CERN/SPS EHN1, H4 beamline (parasitic to RD51/DRD1)

TIMING MEASUREMENTS COMPARISON : PMT+90Sr SOURCE/TESTBEAM

MiniCactus v1, Chip#6, pixel 8, 0.5 x 1 mm², 200 μm



Bias Voltage (V)

→ In-lab measurements with 90Sr betas allow to predict actual performance with MIPs



Have to select MIP-like betas by cutting out low energy deposits in PMT

MiniCACTUS_V2 Sensor Chip

Irfu : Yavuz Degerli, Fabrice Guilloux, Jean-Pierre Meyer, Philippe Schwemling IFAE : Raimon Casanova, Yujin Gan, Sebastian Grinstein



- ~ 2 times larger than MiniCACTUS
- 0.5 mm x 1 mm (baseline), 1 mm x 1 mm and
 0.5 mm x 0.5 mm diodes
- 50 μm x 150 μm and 2 50 μm x 50 μm small test diodes
- 3 different preamps
- New multistage discriminator with programmable hysteresis
- Improved layout for better mixed-signal coupling rejection
- CEA-IRFU & IFAE-Barcelona coll.
- Submitted in May 2023, chips came back from post-processing end May 2024

First look at MiniCactus v2



Analog



PMT

Digital

Analog/Digital couplings are gone !

MiniCACTUS_V2 Sensor Chip

- 3 different preamps implemented in MiniCACTUS_V2
- 2 new preamps (CSA_new and VPA) designed by IFAE-Barcelona for better jitter and reduced ToT



VPA : new voltage preamp

June-July 2024 first testbeam results



TD DUT-MCPPMT After Time Walk Correction CSA1 Pixel1-2 @350V Std Dev: 8 97e-11 120 Constant 125.17 ± 1.52 Neat: 8, Ne-12 + 8, Me-13 Signa 6.76+11 + 8.36+12 100 what his same of 80 8 60 -20 -1.00 -0.75 -0.50 -0.25 0.00 0.25 0.50 0.75 1.00 Time Difference(s) 1e - 9

Data cleaning (cut the noise)

- Sigma before time walk correction: 219 ps
- Sigma matrix after time walk correction:

Sig(DUT-MCP)	Sig(DUT-PMT)	Sig(MCP-PMT)	
67.8 ps	88.1 ps	72.3 ps	

Reverse the matrix to get the sigma of the devices:





Beamline MCP, MiniCactus v2, PMT \rightarrow

 175μ chip, 0.5 mm x 0.5 mm pixel, 300 V

can extract time resolution of the

Testbeam setup has three

three devices

time measurement devices :





MiniCactus v1/v2 comparison



- \bullet Time resolution of v1 and v2 similar for same pixel geometry and identical thickness
- New front-ends have similar performance (before optimization) to old front-end
- \bullet 0.5 mm x 0.5 mm better than 0.5 mm x 1 mm pixels
- \bullet Best result so far on 0.5 x 0.5 mm pixel, thickness 175 μ



How to improve further ?

- Add intrinsic gain to :
 - Improve S/N \rightarrow Improve on time resolution
 - Reduce FE power consumption
 - Reduce pixel pitch
- Ultimate long term goal is reaching 20 ps resolution



TCAD simulation of structures with gain layer

MiniCACTUS-GL Layout





Electric field for one diode with external rings

- DJ-LGAD concept (buried PN-junction implemented by the foundry)
- Total area = 10 mm², 6 different chips with different diodes

Optimization of Buried PN-Junction Parameters



- Gain \geq 10 seems possible

Submission status

- Test structures (passive sensors) have been submitted in May 2024 LF15A MPW
- Six different layouts, identified as promising by TCAD
- Production implied only minimal modifications to LF15A standard process
 - Changes of implant energies for two layers
 - Addition of one Customer Reserved Layer
- HR wafers (same as MiniCactus) → postprocessing underway
- 30 u epi wafers \rightarrow hope is to get rid of postprocessing, diced chips being shipped
- Expect to have HR chips back from dicing/postprocessing by end of 2024

Conclusions and perspectives

- Short term : In-lab and test-beam tests of MiniCactus v2
- Medium term : investigate test structures with integrated gain layer.
- If test structures work, integrate front-end, and submit a MiniCactus like design in LF15A (end 2025 ?)
- Publications :
 - MiniCACTUS: A 65 ps Time Resolution Depleted Monolithic CMOS Sensor (arXiv:2309.08439, NSS 2022 conference)
 - MiniCACTUS: Sub-100 ps timing with depleted MAPS, Nucl.Instrum.Meth.A 1039 (2022) 167022, VCI 2022 conference)
 - CACTUS: A depleted monolithic active timing sensor using a CMOS radiation hard technology (arXiv:2003.04102, JINST 15 (2020) 06, P06011)

Backup

LF15A radiation hardness

0 Mrad @Room Temp 149 Mrad @Room Temp 149 Mrad @Low Temp -15°C





[[]I. Mandic et al. NIM A 903, 2018]

- → Radiation tests at CERN-SPS with **proton** beam on **LF-CPIX** chip (**CPPM**)
- ightarrow 14% increase of noise after irradiation with cooling

Comparison of time resolution of unirradiated and 10¹⁴ 1 MeV neq chips



Senso	r HV bias (V)	Conditions	Temp. (°C)	Time res. (ps)	MPV (mV)
Unirradiated 300	u 400	testbeam, MCPMT time reference	room	78.97 ± 1.36	201.9 ± 0.5
Unirradiated 300	u 400	90Sr, PMT time reference*	room	104.5 ± 2.30	195.7 ± 2.3
Unirradiated 300	u 280	testbeam, MCPMT time reference	room	89.11 ± 1.56	200.9 ± 0.5
Irradiated 300 u	280	90 Sr, PMT time reference	20	108.2 ± 3.2 (PMT subt.)	108.2 ± 3.2
Irradiated 300	u 320	90 Sr, PMT time reference	20	132.9 ± 5.0 (PMT subt.)	113.5 ± 0.8
Irradiated 300	u 320	90 Sr, PMT time reference	-15	87.9 ± 4.7 (PMT subt.)	132.7 ± 0.6

Irradiation at 10¹⁴ n_{eq} worsens time resolution by 18 % w.r.t. unirradiated at 20 °C

Cooling at -15°C brings time resolution more or less back to unirradiated performance (less dark current fluctuations)

*PMT resolution for 90 Sr betas estimated to be 71.3 ps ± 1.7 ps

ELECTRIC FIELDS



Backside versus top biasing \rightarrow Need backside polarization to ensure best charge collection and signal shape uniformity!

*Depleted MAPS

TIMING WITH HV-CMOS/DMAPS*

- The objective of our R&D is the development of a monolithic timing sensor in a commercial HV-CMOS process for future high energy physics experiments or for LHC upgrades (timing detectors, after phase 2 upgrades)
- □ LFoundry 150 nm HV-CMOS is one of the CMOS processes studied extensively for the CMOS option of the ATLAS Inner Tracker Upgrade
- Several large size demonstrators already designed and tested for tracking applications (LF-CPIX, LF-MONOPIX1, LF-MONOPIX2) in this process with proven radiation hardness (Bonn, IRFU and CPPM coll.)

HV-CMOS Sensor Pixel



- DNW/HR p-substrate charge collection diode
- HV (≥ 300 V) applied on the substrate (from top or back)
- Large depletion depth (\geq 300 μ m)
- Charge collection by <u>drift</u> (fast)
- No internal amplification
- Electronics can be integrated inside charge collection diode

ON-CHIP FRONT-END



TESTBENCH OF MINICACTUS IN TESTBEAM



Time reference RD-51 MCPs (resolution < 10 ps)

Pixel position scan at 20 keV with photons (data taken at Synchrotron Soleil)



Х

Used a pencil beam (50 microns by 50 microns) to scan pixel surface

No non-uniformity found

CACTUS* DEVELOPMENT

- □ The first demonstrator called **CACTUS** for timing in LF 150 nm process designed in 2019
- The front-end in CACTUS is based on an in-pixel fast preamplifier followed by a leading edge discriminator
- Time walk corrections done off-line by ToT measurement
- Expected timing resolution from Cadence & TCAD simulations: 50-100 ps

*CMOS ACtive Timing μSensor





The CACTUS demonstrator on PCB (chip size : 1 cm x 1 cm)